

# TRANSMITTAL FORM

*Do not be used for correspondence after initial filing*

FEB 14 2003

Application Number	09/616,372
Filing Date	7/13/2000
First Named Inventor	KOMURA
Group Art Unit	2881
Examiner Name	Souw
Attorney Docket Number	01-50

## ENCLOSURES (check all that apply)

<input type="checkbox"/> Fee Transmittal Form	<input type="checkbox"/> Assignment Papers (for an Application)	<input type="checkbox"/> After Allowance Communication to Group
<input checked="" type="checkbox"/> Fee Attached	<input checked="" type="checkbox"/> Drawing(s)	<input type="checkbox"/> Appeal Communication to Board of Appeals and Interferences
<input type="checkbox"/> Amendment / Response	<input type="checkbox"/> Appendix showing amendments to specification and claims	<input type="checkbox"/> Appeal Communication to Group (Appeal Notice, Brief, Reply Brief)
<input type="checkbox"/> After Final	<input type="checkbox"/> Petition Routing Slip (PTO/SB/69) and Accompanying Petition	<input type="checkbox"/> Proprietary Information
<input type="checkbox"/> Affidavits/declaration(s)	<input type="checkbox"/> To Convert a Provisional Application	<input type="checkbox"/> Status Letter
<input type="checkbox"/> Extension of Time Request	<input type="checkbox"/> Power of Attorney, Revocation Change of Correspondence Address	<input checked="" type="checkbox"/> Additional Enclosure(s) (please identify below):
<input type="checkbox"/> Express Abandonment Request	<input type="checkbox"/> Terminal Disclaimer	Page 1904 of McGraw-Hill Dictionary of Science and Technology
<input type="checkbox"/> Information Disclosure Statement	<input type="checkbox"/> Small Entity Statement	
<input type="checkbox"/> Certified Copy of Priority Document(s)	<input type="checkbox"/> Request of Refund	
<input type="checkbox"/> Response to Missing Parts/Incomplete Application	Remarks	
<input type="checkbox"/> Response to Missing Parts under 37 CFR 1.52 or 1.53		

## SIGNATURE OF APPLICANT, ATTORNEY, OR AGENT

Firm or Individual name	Law Offices of David G. Posz
Signature	<i>David G. Posz</i>
Date	14 February 2003

## OIPE CERTIFICATE OF HAND DELIVERY

I hereby certify that this correspondence is being hand delivered to and deposited with the USPTO at the Customer Service Window, Office of Initial Patent Examination, Crystal Plaza Building 2, Room 1B03, 2011 South Clark Place, Arlington, VA 22202 on the below-indicated date and is addressed to: Assistant Commissioner for Patents, Washington, DC 20231.

Type or printed name	James E. Barlow	Date	14 February 2003
Signature	<i>James E. Barlow</i>		



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# FEE TRANSMITTAL for FY 2003

Patent fees are subject to annual revision.

☐ Applicant claims small entity status. See 37 CFR 1.27

TOTAL AMOUNT OF PAYMENT (\$)**930.00**

## Complete if Known

Application Number **09/616,372**

Filing Date **7/13/2000**

First Named Inventor **KOMURA**

Examiner Name **Souw**

Group/Art Unit **2881**

Attorney Docket No. **01-50**

## METHOD OF PAYMENT (check one)

1. ☐ The Commissioner is hereby authorized to charge indicated fees and credit any overpayments to:

Deposit  
Account  
Number

**50-1147**

Deposit  
Account  
Name

**LAW OFFICES OF DAVID G. POSZ**

☒ Charge Any Additional Fee Required  
Under 37 CFR 1.16 and 1.17

2. ☒ Payment Enclosed:

☒ Check ☐ Money  
Order ☐ Other

## FEE CALCULATION (continued)

### 3. ADDITIONAL FEES

Large Entity		Small Entity		Fee Description	Fee Paid
Fee Code	Fee (\$)	Fee Code	Fee (\$)		
1051	130	2051	65	Surcharge - late filing fee or oath	
1052	50	2052	25	Surcharge - late provisional filing fee or cover sheet	
1053	130	1053	130	Non-English specification	
1812	2,520	1812	2,520	For filing a request for reexamination	
1804	920*	1804	920*	Requesting publication of SIR prior to Examiner action	
1805	1,840*	1805	1,840*	Requesting publication of SIR after Examiner action	
1251	110	2251	55	Extension for reply within first month	
1252	410	2252	205	Extension for reply within second month	
1253	930	2253	460	Extension for reply within third month	930.00
1254	1450	2254	725	Extension for reply within fourth month	
1255	1970	2255	985	Extension for reply within fifth month	
1401	320	2401	160	Notice of Appeal	
1402	320	2402	160	Filing a brief in support of an appeal	
1403	280	2403	140	Request for oral hearing	
1451	1,510	1451	1,510	Petition to institute a public use proceeding	
1452	110	2452	55	Petition to revive - unavoidable	
1453	1,300	2453	650	Petition to revive - unintentional	
1501	1300	2501	650	Utility issue fee (or reissue)	
1502	470	2502	235	Design issue fee	
1503	630	2503	315	Plant issue fee	
1460	130	1460	130	Petitions to the Commissioner	
1807	50	1807	50	Petitions related to provisional applications	
1806	180	1806	180	Submission of information Disclosure Stmt	
8021	40	8021	40	Recording each patent assignment per property (times number of properties)	
1809	750	2809	375	Filing a submission after final rejection (37 CFR § 1.129(a))	
1810	750	2810	375	For each additional invention to be examined (37 CFR § 1.129(b))	
Other fee (specify) _____					
Other fee (specify) _____					
*Reduced by Basic Filing Fee Paid					
SUBTOTAL (3)					(\$) <b>930.00</b>

## FEE CALCULATION

### 1. BASIC FILING FEE

Large Entity		Small Entity		Fee Description	Fee Paid
Fee Code	Fee (\$)	Fee Code	Fee (\$)		
1001	750	2001	375	Utility filing fee	
1002	330	2002	165	Design filing fee	
1003	520	2003	260	Plant filing fee	
1004	750	2004	375	Reissue filing fee	
1005	160	2005	80	Provisional filing fee	
SUBTOTAL (1)					(\$) <b>0</b>

### 2. EXTRA CLAIM FEES

Extra Claims		Fee from Below		Fee Paid
Total Claims				
20	-22** =	0	18	= 0
Independent Claims	4	-4** =	84	= 0
Multiple Dependent				
**or number previously paid, if greater. For Reissues, see below				
Large Entity		Small Entity		Fee Description
Fee Code	Fee (\$)	Fee Code	Fee (\$)	
1202	18	2202	9	Claims in excess of 20
1201	84	2201	42	Independent claims in excess of 3
1203	280	2203	140	Multiple dependent claim, if not paid
1204	84	2204	42	**Reissue independent claims over original patent
1205	18	2205	9	**Reissue claims in excess of 20 and over original patent
SUBTOTAL (2)				
(\$) <b>0</b>				

## SUBMITTED BY

Name (Print/Type)	<b>JAMES E. BARLOW</b>	Registration No. (Attorney Agent)	<b>32,377</b>	Telephone	<b>(202) 416-1638</b>
Signature		Date	<b>14 February 2003</b>		

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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicants: Komura et al.

Atty. Dkt.: 1-50

Serial No.: 09/616,372

Group Art Unit: 2881

Filed: July 13, 2000

Examiner: SOUW, BERNARD E

Title: METHOD FOR MEASURING  
THICKNESS OF OXIDE FILM

Assistant Commissioner for Patents  
Washington, D.C. 20231

Date: 14 February 2003

**CERTIFICATE OF HAND DELIVERY**

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Typed Name: JAMES E. PARLOW

Signature: James E. Parlow

**AMENDMENT**

Sir:

In response to the Office Action mailed 14 August 2002, please enter the following amendments and consider the appended remarks.

**IN THE SPECIFICATION**

Please replace the paragraph of lines 16-21 of page 2 with the following:

According to a first aspect of the present invention, a thickness of an oxide film is measured by controlling an exposure time, or period, during which the oxide film is exposed to the atmosphere from the formation of the oxide film to the measurement of the thickness. As a result, the thickness can be measured accurately. The measured thickness may be corrected in accordance with the exposure period.

Please replace the paragraph beginning on line 22 of page 2 and ending on line 2 of page 3 with the following:

According to a second aspect of the present invention, a thickness of an oxide film is measured after washing a surface of the oxide film. The washing of the oxide film removes deposits from the surface of the oxide film, resulting in accurate measurement of the thickness of the oxide film. The exposure period, during which the oxide film is exposed from the washing to the measurement of the thickness can be controlled to more precisely measure the thickness.

Please replace the paragraph of lines 22-24 of page 3 with the following: